

IEEE SCC20 15-1 PLENARY
Tuesday May 12, 2015

1) CALL TO ORDER (*Mike Seavey*)

2) ANOUNCEMENTS

3) INTRODUCTIONS/ATTENDANCE SHEET (*All*)

Attendance sheet passed around

4) 15-1 MEETING AGENDA (*Mike Seavey*)

Agenda reviewed – no comments

Tour of the “demo area” at 4 pm on Wednesday

Move Steering to 2 pm to finish before the tour

5) CALL FOR PATENTS (*Mike Seavey*)

Mike Seavey presented the updated patent slides and notified working group chairs to grab the latest version from myProject.

See <../IEEE 2015 Patent Slideset/slideset.pdf>

As an example, a letter of assurance is underway between Teradyne and the IEEE concerning DTIF. LOA submitted when the standard was originally developed can't be found.

6) CHAIRS INITIAL REPORT (*Mike Seavey*)

Initial Chair's Report <SCC20 15-1 Chairs Initial Report.pdf>

SCC20 Organization chart will get uploaded to SCC20 website after the meeting

Standards tracking sheet – in order to keep a standard active, we must have a revision before the 10 year clock expires

Reaffirmations are no longer an option. Must run a ballot to keep the standard active.

TAD WG

- Test Description revision changes to simplify
- Working on digital and serial bus testing and propose changes to Test Description and UUT Description

TII WG

- Test Adapter and Test System have been published by IEEE
- Review whether we continue with the 1871 PARs – identify commitment
 - Intrinsic Path
 - Test Orchestration

HI WG

- 1505.1 start discussion on revision
- 1693 discussion on withdrawing the PAR
- 1514
- 1505.3 ballot resolution

TC91

- Need to understand how recommended practices map to IEC

7) WORKING GROUP PLANS FOR THIS MEETING

DMC WGs/Study Group– *M. Seavey*
TAD WGs– *I. Neag / A. Jain*
TII WGs– *C. Gorringer / T. Lopes*
HI WGs– *S. Mann / R. Spinner*

8) IEC TC91 WG 15 REPORT (*Osamu Karatsu*)

See <see IEC activity report to SCC20 2015 May.pdf>

9) ADJOURN TO SUBCOMMITTEES & WORKING GROUPS